Table of Contents

Please Note Manuals are NOT printed in color

The Basics 1-1
Objectives 1-1
Scientific / Engineering Notation 1-1
Voltage 1-2
Current 1-2
Resistance 1-2
Using Ohm's Law to Verify Device Specifications 1-3
Digital Numbers 1-5
Digital Logic 1-8

Overview of Semiconductors and ATE 2-1
Objectives 2-1
Wafers, Die, and Packages 2-1
ATE - Automated Test Equipment 2-5
Semiconductor Technologies 2-5
Digital and Analog Circuits 2-6
Types of ATE Systems 2-7
Tester Interface Boards 2-13
Wafer Probing 2-14
Probe Cards 2-16
Multi-site Probe Cards 2-17
Device Handlers 2-18
Temperature Forcing Units 2-20

Introduction to Test 3-1
Objectives 3-1
The Bottom Line 3-1
Basic Terms 3-1
What will be Tested? 3-6
Why Test? 3-9
Defects 3-10
What is The Correct Way to Test? 3-14
Quality, Reliability, and Environmental Testing 3-17
Shake and Bake 3-20
Voltage Stress 3-21
Binning 3-23
Program Flow 3-24
Test Summary 3-25
Traceability 3-26
Introduction to Test Review 3-27

Test System Architecture 4-1
Objectives 4-1
Basic Terms 4-1
The Test System 4-1

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What's in a Test System? 4-3
DC Instrumentation 4-7
Functional/AC Instrumentation 4-17
Mechanical. 4-40
Software 4-41
Basic Guidelines of Digital Semiconductor Test Engineering 4-44
Test System Architecture Review 4-45

Device Specifications 5-1
Objectives 5-1
Basic Terms 5-1
The Design Specification 5-1
The Test Specification 5-2
The Device Specification 5-2
Test Conditions and Limits 5-2
Parameters that Apply to DC Parametric Testing 5-2
Parameters that Apply to Functional and AC Testing 5-3
Logical Functions 5-3
Reading Device Specifications 5-3
256 x 4 RAM Specifications. 5-5
Interpreting the Device Specification 5-8
Device Specifications and Test Conditions 5-9

Shorts and Opens - PMU Method 6-1
Objectives 6-1
Why Test for Shorts and Opens? 6-1
Shorts and Opens Serial Static Method 6-1
Shorts and Opens -Trouble Shooting 6-4
Power Bus Shorts Test 6-4
Shorts and Opens - Key Points 6-5

Verifying DC Parameters 7-1
Objectives 7-1
Basic Terms 7-1
The VPMU 7-2
DC Tests and the Hidden Resistance 7-3
VOH/IOH 7-4
VOL/IOL. 7-8
IDD Gross Current. 7-13
IDD Static Current 7-17
IDDQ Current 7-21
IDD Dynamic Current. 7-25
Input Currents (IIL/IIH). 7-29
Resistive Inputs Pullups and Pulldowns 7-36
Output Fanout 7-37
DC Fanout 7-37
AC Fanout 7-37
High Impedance Currents (IOZL/IOZH). 7-39
Input Clamp (VI). 7-44
Output Short Circuit Current (IOS). 7-47

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Functional Testing . . . 8-1
Objectives: . . . 8-1
Introduction to Functional Testing . . . 8-1
Basic Terms . . . 8-1
Functional Testing . . . 8-2
Vector Data . . . 8-13
Executing a Functional Test . . . 8-14
Equation Based Timing . . . 8-18
Functionally Testing a Device . . . 8-19
Specification Test Conditions for the D Flip-Flop . . . 8-23
Standard Functional Tests . . . 8-29
Opens and Shorts - Functional Method . . . 8-29
VIL/VIH . . . 8-34
VOL/IOL VOH/IOH Functional Test . . . 8-37
Resistive Output Loading . . . 8-40
Input/Output Levels Relationship . . . 8-41
Functional Z State / High Impedance Testing . . . 8-42
Open Drain / Open Source Outputs . . . 8-45

Testing AC Parameters . . . 9-1
Objectives: . . . 9-1
AC Parametric Testing . . . 9-1
. . . 9-13
AC Specifications from 256 x 4 Static RAM Data Sheet . . . 9-14
Developing Functional Timing . . . 9-15

Device Characterization . . . 10-1
Objectives . . . 10-1
Characterization Overview . . . 10-1
Test Vectors and Characterization . . . 10-2
Defining Characterization Parameters . . . 10-2
Common Characterization Parameters . . . 10-3
Use of Test System Tools . . . 10-4
Binary Search - Output Timings . . . 10-11

Design For Testability . . . 11-1
Objectives . . . 11-1
Design For Testability . . . 11-1
Functional Testing and DFT . . . 11-1
Fault Models . . . 11-2
Automatic Test Pattern Generation . . . 11-4
Fault Coverage . . . 11-6
Types of Structured DFT . . . 11-8
Boundary Scan IEEE 1149.1 . . . 11-14
BIST . . . 11-20

Test Vector Development . . . 12-1
Objectives . . . 12-1
Test Vectors . . . 12-1
Example Vector File . . . 12-1

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Working with the Design Engineer 12-2
Creating Vectors by Hand 12-2
Tester Options (Memory Considerations) 12-3
Test Vector Examples 12-3
Simulation Data 12-7
Simulation for Test. 12-9

Test Program Development Issues 13-1
Objectives: 13-1
What is the Primary Purpose of the Test Program? 13-1
Other Considerations. 13-2
Initializing the Program 13-2
Verifying the Test Setup 13-2
Power On Sequencing. 13-3
Power Off Sequencing 13-4

Creating a Test Program 14-1
Objectives: 14-1
Developing the Test Plan from the Device Specification 14-1
Designing the Test Hardware 14-2
Writing the Test Program 14-2
interface Board Tests 14-3
Tester Diagnostics 14-3
Running the Program the First Time 14-4
Verifying the Functional Test Setup 14-4
A Brief Discussion on Test Vectors 14-5

Troubleshooting 15-1
Objectives 15-1
Where to Begin 15-2
Example: IIL/IIH Test Failures 15-4
Debug Tools 15-5

Qualifying and Documenting the Test Program 16-1
Objectives 16-1
Qualification 16-1
Verify testing on handlers and probers 16-2
Documenting the Test Program 16-2

CMOS Device Latchup 17-1
Objectives: 17-1
What is Latch–up? 17-1
Latch–up Testing 17-3
Test Patterns 17-4
Test Procedure Summary 17-6
Applying Test Stimulus 17-6

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Glossary Glossary-1

Answers to Review Questions Answers-1

Chapter 3 - Introduction to Test Answers-1
Chapter 4 - Test System Architecture Answers-4
Chapter 5 - Workbook Exercise Answers-6
Chapter 5 - Device Specification Answers-8
Chapter 6 - Opens and Shorts Answers-9
Chapter 7 - DC Tests Answers-10
Chapter 8 - Functional Test Answers-12
Chapter 9 - AC Testing Answers-15
Chapter 10 - Device Characterization Answers-17
Chapter 11 - Design for Testability Answers-18
Chapter 12 - Test Vector Development Answers-21
Chapter 13 - Test Program Development issues Answers-22
Chapter 14 - Creating a Test Program Answers-24
Chapter 15 - Troubleshooting Answers-25
Chapter 16 - Qualifying and Documenting the Test Program Answers-27

Index Index-1

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